

**Search Notes**

Application/Control No.

10/530,285

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

BETEILLE, FABIEN

Art Unit

1792

**SEARCHED**

Class	Subclass	Date	Examiner
216	33	1/2/2009	BT
216	59	1/2/2009	BT
216	65	1/2/2009	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>216</b>	<b>33</b>	<b>1/2/2009</b>	<b>BT</b>
216	59	1/2/2009	BT
216	65	1/2/2009	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update inventor's names search	01/02/2009	BT
Update keywords search using databases in EAST	1/2/2009	BT